## MT3401A

# P-Channel Enhancement Mode Field Effect Transistor

### **Product Summary**

- VDS= -30V
- ID= -4.2A (VGS= -10V)
- RDS(ON)  $\leq$  45m  $\Omega$  @VGS= -10V
- RDS(ON)  $\leq$  55m  $\Omega$  @VGS= -4.5V
- RDS(ON)  $\leq$  75m  $\Omega$  @VGS= -2.5V

#### **Features**

- · Advanced Trench Process Technology.
- · High dense cell design for ultra low R DS(ON).
- · Lead free product is acquired.
- · RoHS Compliant.

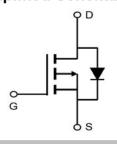
### **Applications**

- · Power Management in Notebook Computer
- · Portable Equipment and Battery Powered Systems

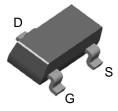


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### **Simplified Schematic**



MARKING DIAGRAM & PIN ASSIGNMENT



SOT-23-3L

### **Absolute Maximum Ratings**(T<sub>A</sub> = 25°C unless otherwise noted)

Symbol	Parameter	Steady State	Units
V <sub>DS</sub>	Drain-Source Voltage	-30	V
Vgs	Gate-Source Voltage	±12	V
I <sub>D</sub>	Continuous Drain Current <sup>1</sup>	-4.2	Α
I <sub>DM</sub>	Pulsed Drain Current <sup>2</sup>	-30	Α
Is	Continuous Source Current (Diode Conduction) 1	-2	Α
PD	Maximum Power Dissipation <sup>1</sup>	1.25	W
T <sub>J</sub> , T <sub>STG</sub>	Operating Junction and Storage Temperature Range	-55 to 150	$^{\circ}$ C

### Notes:

- 1. Surface Mounted on 1" x 1" FR4 Board, t≤10 Sec.
- 2. Pulse width limited by maximum junction temperature.

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### **Thermal Resistance Ratings**

Symbol	Parameter		Typical	Maximum	Unit
R <sub>thJA</sub>	Maximum Junction-to-Ambient	t≦10 Sec	65	90	
		Steady State	85	125	°C/W
R <sub>thJF</sub>	Maximum Junction-to-Foot (Drain)	Steady State	43	60	

### Electrical Characteristics (T<sub>A</sub>=25°C, unless otherwise noted)

Symbol	Parameter	Test Condition	Min	Тур	Max	Unit
• Stati	c Characteristics					
BVDSS	Drain-Source Breakdown Voltage	Vgs= 0V, Ip= -250µA	-30	_	-	V
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = -250μA	-0.7	-1	-1.5	V
I <sub>GSS</sub>	Gate-Body Leakage Current	V <sub>DS</sub> = 0V, V <sub>GS</sub> = ±12V	-	-	±100	nA
	Zero Gate Voltage Drain Current	V <sub>DS</sub> = -24V, V <sub>GS</sub> = 0V	-	-	-1	μА
I <sub>DSS</sub>		V <sub>DS</sub> = -24V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 85°C	-	-	-30	
	Drain Source On State Resistance <sup>a</sup>	V <sub>GS</sub> = -10V, I <sub>D</sub> = -4.2A		45		mΩ
$R_{DS(on)}$		V <sub>GS</sub> = -4.5V, I <sub>D</sub> = -4A		55		
		V <sub>GS</sub> = -2.5V, I <sub>D</sub> = -1A		75		
<b>g</b> fs	Forward Transconductance <sup>a</sup>	V <sub>DS</sub> = -5V, I <sub>D</sub> = -5A	7	11	-	S
V <sub>SD</sub>	Diode Forward Voltage <sup>a</sup>	I <sub>S</sub> = -1A, V <sub>GS</sub> = 0V	-	-0.77	-1	V
• Dyna	mic Characteristics <sup>b</sup>		,			
C <sub>iss</sub>	Input Capacitance		-	720	-	
Coss	Output Capacitance	V <sub>DS</sub> = -15V, V <sub>GS</sub> =0V, f=1MHz	-	90	-	pF
C <sub>rss</sub>	Reverse Transfer Capacitance		-	65	-	1
Qg	Total Gate Charge		-	11.5	14	
Qgs	Gate-Source Charge	V <sub>DS</sub> = -15V, V <sub>GS</sub> = -4.5V, I <sub>D</sub> = -2.5A	-	1.56	-	nC
Q <sub>gd</sub>	Gate-Drain Charge		-	2.2	-	1
t <sub>d(on)</sub>	Turn-On Delay Time		-	8.3	12	
t <sub>r</sub>	Rise Time	$V_{DD} = -15V, R_L = 15\Omega$	-	7.6	15	nSec
T <sub>d(off)</sub>	Turn-Off Delay Time	$I_{D}$ = -1.0A, $V_{GEN}$ = -10V, $R_{G}$ = 6 $\Omega$	-	26	46	
t <sub>f</sub>	Fall Time		-	5.6	10	1
Rg	Gate Resistance	V <sub>GS</sub> =0, V <sub>DS</sub> =0, f=1MHz	-	8	-	Ω
t <sub>rr</sub>	Body Diode Reverse Recovery Time	1. 10.17/11. 1000/	-	11	-	nSec
Qrr	Body Diode Reverse Recovery Charge	I <sub>F</sub> = -4A, di/dt = 100A/μs	-	6	-	nC

#### Note:

a. Pulse test; pulse width  $\leq$  300µs, duty cycle  $\leq$  2%.

b. Guaranteed by design, not subject to production testing.

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### **Characteristics Curve**

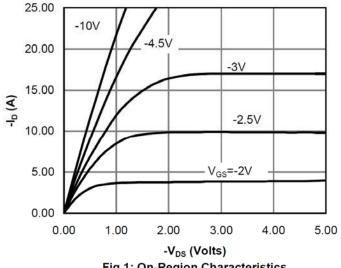


Fig 1: On-Region Characteristics

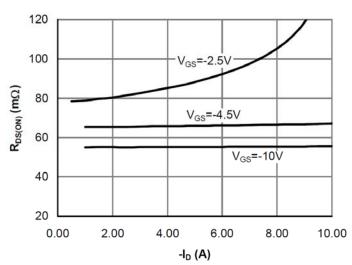


Figure 3: On-Resistance vs. Drain Current and **Gate Voltage** 

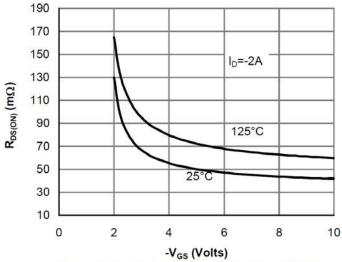


Figure 5: On-Resistance vs. Gate-Source Voltage

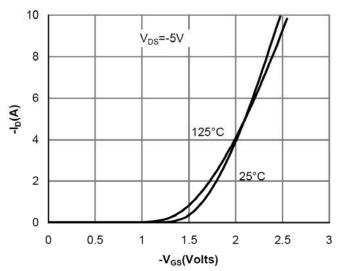


Figure 2: Transfer Characteristics

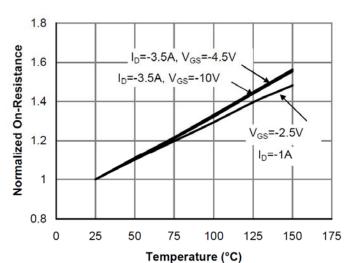


Figure 4: On-Resistance vs. Junction **Temperature** 

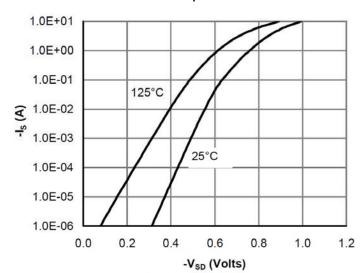


Figure 6: Body-Diode Characteristics

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### **Characteristics Curve**

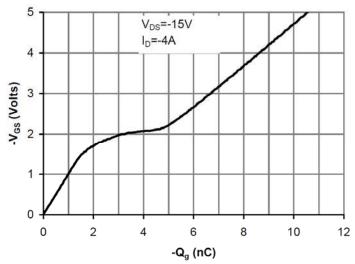


Figure 7: Gate-Charge Characteristics

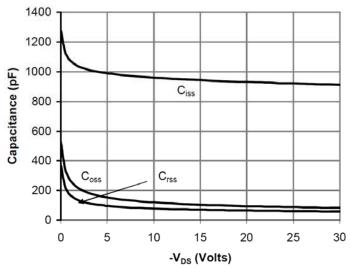


Figure 8: Capacitance Characteristics

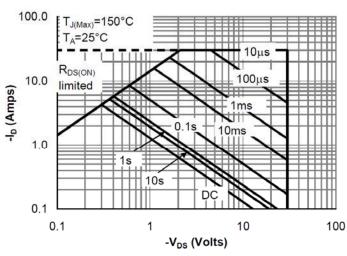


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

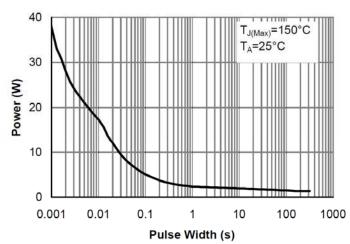


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

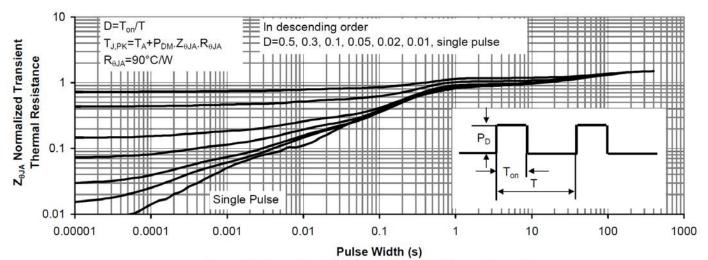
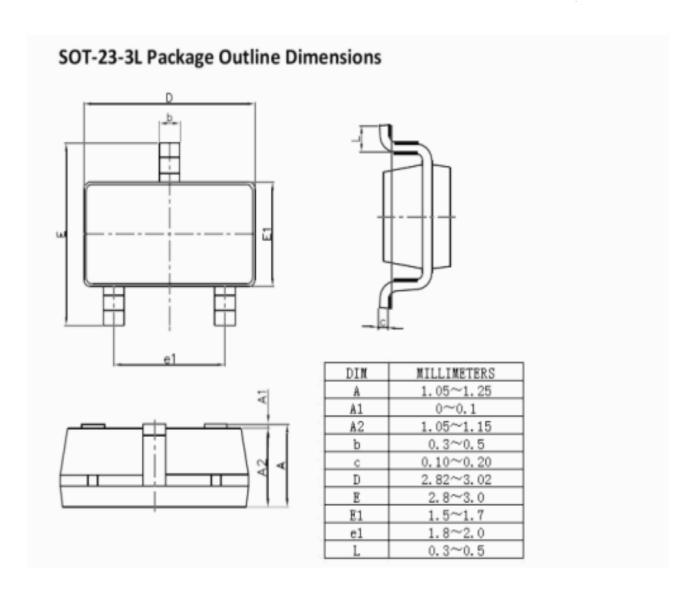


Figure 11: Normalized Maximum Transient Thermal Impedance

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#### NOTE

- 1. PACKAGE BODY SIZES EXCLUDE MOLD FLASH OR GATE BURRS. MOLD FLASH AT THE NON-LEAD SIDES SHOULD BE LESS THAN 5 MILS EACH.
- 2. TOLERANCE  $\pm 0.100$  mm (4 mil) UNLESS OTHERWISE SPECIFIED.
- 3. DIMENSION L IS MEASURED IN GAUGE PLANE.
- 4. CONTROLLING DIMENSION IS MILLIMETER. CONVERTED INCH DIMENSIONS ARE NOT NECESSARILY EXACT.
- 5. ALL DIMENSIONS ARE IN MILLIMETERS.

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